

**FAIRCHILD**  
SEMICONDUCTOR™

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## 100360 Low Power Dual Parity Checker/Generator

### General Description

The 100360 is a dual parity checker/generator. Each half has nine inputs; the output is HIGH when an even number of inputs are HIGH. One of the nine inputs ( $I_a$  or  $I_b$ ) has the shorter through-put delay and is therefore preferred as the expansion input for generating parity for 16 or more bits. The 100360 also has a Compare ( $\bar{C}$ ) output which allows the circuit to compare two 8-bit words. The  $\bar{C}$  output is LOW when the two words match, bit for bit. All inputs have 50 k $\Omega$  pull-down resistors.

### Features

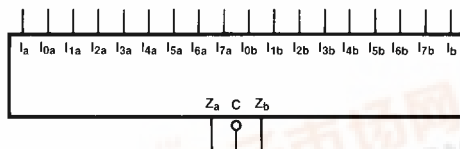
- Lower power than 100160
- 2000V ESD protection
- Pin/function compatible with 100160
- Voltage compensated operating range = -4.2V to -5.7V
- Min to Max propagation delay 35% tighter than 100160
- Available to industrial grade temperature range

### Ordering Code:

Order Number	Package Number	Package Description
100360PC	N24E	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-010, 0.400 Wide
100360QC	V28A	28-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.450 Square
100360QI	V28A	28-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.450 Square Industrial Temperature Range (-40°C to +85°C)

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

### Logic Symbol



### Pin Descriptions

Pin Names	Description
$I_a, I_b, I_{0a}, I_{0b}$	Data Inputs
$Z_a, Z_b$	Parity Odd Outputs
$\bar{C}$	Compare Output

### Truth Table

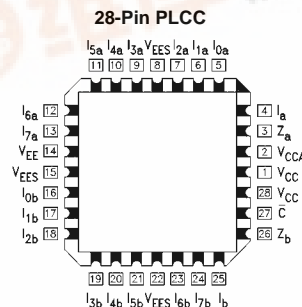
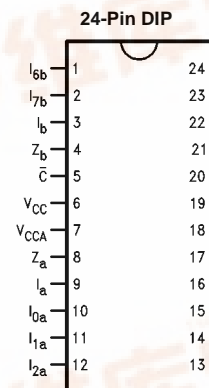
(Each Half)

Sum of HIGH Inputs	Output Z
Even	HIGH
Odd	LOW

### Comparator Function

$$\bar{C} = (I_{0a} \oplus I_{1a}) + (I_{2a} \oplus I_{3a}) + (I_{4a} \oplus I_{5a}) + (I_{6a} \oplus I_{7a}) + (I_{0b} \oplus I_{1b}) + (I_{2b} \oplus I_{3b}) + (I_{4b} \oplus I_{5b}) + (I_{6b} \oplus I_{7b})$$

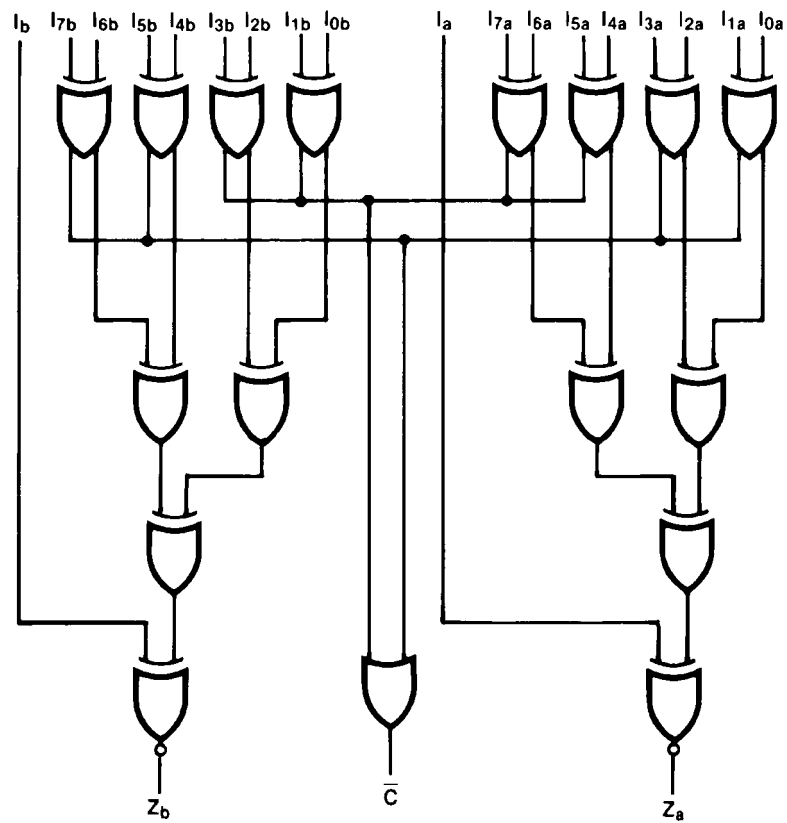
### Connection Diagrams



100360 Low Power Dual Parity Checker/Generator



## Logic Diagram



**Absolute Maximum Ratings**(Note 1)

Storage Temperature ( $T_{STG}$ )	-65°C to +150°C
Maximum Junction Temperature ( $T_J$ )	+150°C
$V_{EE}$ Pin Potential to Ground Pin	-7.0V to +0.5V
Input Voltage (DC)	$V_{EE}$ to +0.5V
Output Current (DC Output HIGH)	-50 mA
ESD (Note 2)	≥2000V

**Recommended Operating Conditions**

Case Temperature ( $T_C$ )	
Commercial	0°C to +85°C
Industrial	-40°C to +85°C
Supply Voltage ( $V_{EE}$ )	-5.7V to -4.2V

**Note 1:** The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum rating. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

**Note 2:** ESD testing conforms to MIL-STD-883, Method 3015.

**Commercial Version****DC Electrical Characteristics** (Note 3)

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ ,  $T_C = 0^\circ C$  to  $+85^\circ C$

Symbol	Parameter	Min	Typ	Max	Units	Conditions
$V_{OH}$	Output HIGH Voltage	-1025	-955	-870	mV	$V_{IN} = V_{IH} (Max)$ or $V_{IL} (Min)$ Loading with 50Ω to -2.0V
$V_{OL}$	Output LOW Voltage	-1830	-1705	-1620		
$V_{OHC}$	Output HIGH Voltage	-1035			mV	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$ Loading with 50Ω to -2.0V
$V_{OLC}$	Output LOW Voltage			-1610		
$V_{IH}$	Input HIGH Voltage	-1165		-870	mV	Guaranteed HIGH Signal for All Inputs
$V_{IL}$	Input LOW Voltage	-1830		-1475	mV	Guaranteed LOW Signal for All Inputs
$I_{IL}$	Input LOW Current	0.50			μA	$V_{IN} = V_{IL} (Min)$
$I_{IH}$	Input HIGH Current $I_{a}, I_b$ $I_{na}, I_{nb}$			340 240	μA	$V_{IN} = V_{IH} (Max)$
$I_{EE}$	Power Supply Current	-100		-50	mA	Inputs OPEN

**Note 3:** The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

**DIP AC Electrical Characteristics**

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
$t_{PLH}$	Propagation Delay	1.10	2.75	1.10	2.75	1.10	2.75	ns	Figures 1, 2
$t_{PHL}$	$I_{na}, I_{nb}$ to $Z_a, Z_b$								
$t_{PLH}$	Propagation Delay	1.10	2.80	1.10	2.80	1.10	2.80	ns	
$t_{PHL}$	$I_{na}, I_{nb}$ to $\bar{C}$								
$t_{PLH}$	Propagation Delay	0.50	1.20	0.60	1.30	0.60	1.30	ns	
$t_{PHL}$	$I_a, I_b$ to $Z_a, Z_b$								
$t_{TLH}$	Transition Time	0.35	1.10	0.35	1.10	0.35	1.10	ns	
$t_{THL}$	20% to 80%, 80% to 20%								

## Commercial Version (Continued)

### PLCC AC Electrical Characteristics

 $V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ 

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $Z_a, Z_b$	1.10	2.75	1.10	2.75	1.10	2.75	ns	Figures 1, 2
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $\bar{C}$	1.10	2.80	1.10	2.80	1.10	2.80	ns	
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_a, I_b$ to $Z_a, Z_b$	0.50	1.20	0.60	1.30	0.60	1.30	ns	
$t_{TLH}$ $t_{THL}$	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	

## Industrial Version

### PLCC DC Electrical Characteristics (Note 4)

 $V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ ,  $T_C = -40^\circ C$  to  $+85^\circ C$ 

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = 0^\circ C$ to $+85^\circ C$		Units	Conditions	
		Min	Max	Min	Max			
$V_{OH}$	Output HIGH Voltage	-1085	-870	-1025	-870	mV	$V_{IN} = V_{IH}$ (Max) or $V_{IL}$ (Min)	Loading with 50Ω to -2.0V
$V_{OL}$	Output LOW Voltage	-1830	-1575	-1830	-1620	mV	$V_{IN} = V_{IH}$ (Min) or $V_{IL}$ (Max)	Loading with 50Ω to -2.0V
$V_{OHC}$	Output HIGH Voltage	-1095		-1035		mV		
$V_{OLC}$	Output LOW Voltage		-1565		-1610	mV		
$V_{IH}$	Input HIGH Voltage	-1170	-870	-1165	-870	mV	Guaranteed HIGH Signal for All Inputs	
$V_{IL}$	Input LOW Voltage	-1830	-1480	-1830	-1475	mV	Guaranteed LOW Signal for All Inputs	
$I_{IL}$	Input LOW Current	0.50		0.50		μA	$V_{IN} = V_{IL}$ (Min)	
$I_{IH}$	Input HIGH Current					μA	$V_{IN} = V_{IH}$ (Max)	
			$I_a, I_b$ 340		340	μA		
			$I_{na}, I_{nb}$ 240		240	μA		
$I_{EE}$	Power Supply Current	-100	-50	-100	-50	mA	Inputs OPEN	

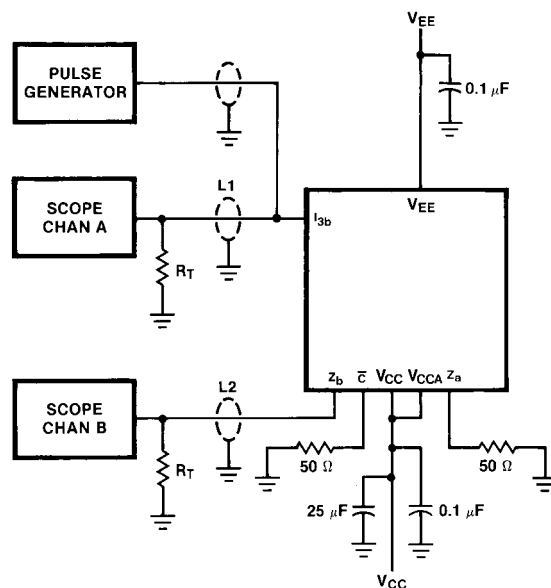
**Note 4:** The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

### PLCC AC Electrical Characteristics

 $V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ 

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $Z_a, Z_b$	1.00	2.75	1.10	2.75	1.10	2.75	ns	Figures 1, 2
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $\bar{C}$	1.00	2.80	1.10	2.80	1.10	2.80	ns	
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_a, I_b$ to $Z_a, Z_b$	0.50	1.20	0.60	1.30	0.60	1.30	ns	
$t_{TLH}$ $t_{THL}$	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	

## Test Circuitry



### Notes:

$V_{CC}, V_{CCA} = +2V, V_{EE} = -2.5V$

$L1$  and  $L2$  = equal length  $50\Omega$  impedance lines

$R_T = 50\Omega$  terminator internal to scope

Decoupling  $0.1 \mu F$  from GND to  $V_{CC}$  and  $V_{EE}$

All unused outputs are loaded with  $50\Omega$  to GND

$C_L$  = Fixture and stray capacitance  $\leq 3$  pF

FIGURE 1. AC Test Circuit

## Switching Waveforms

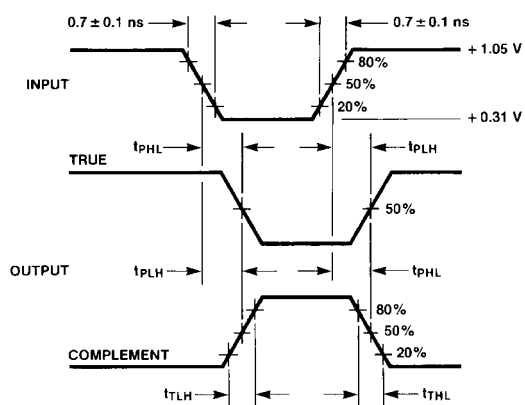
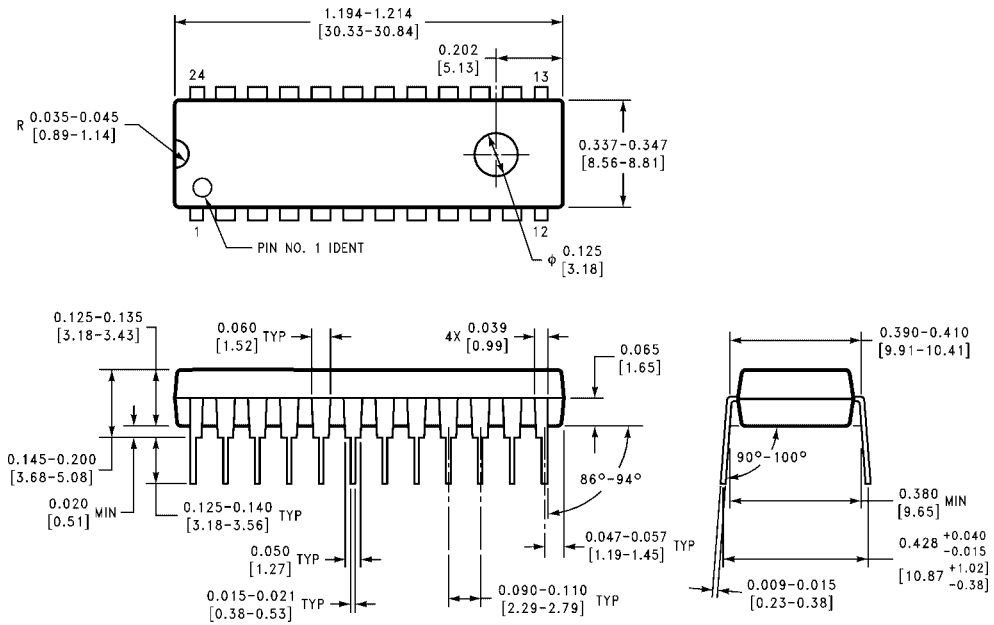


FIGURE 2. Propagation Delay and Transition Times

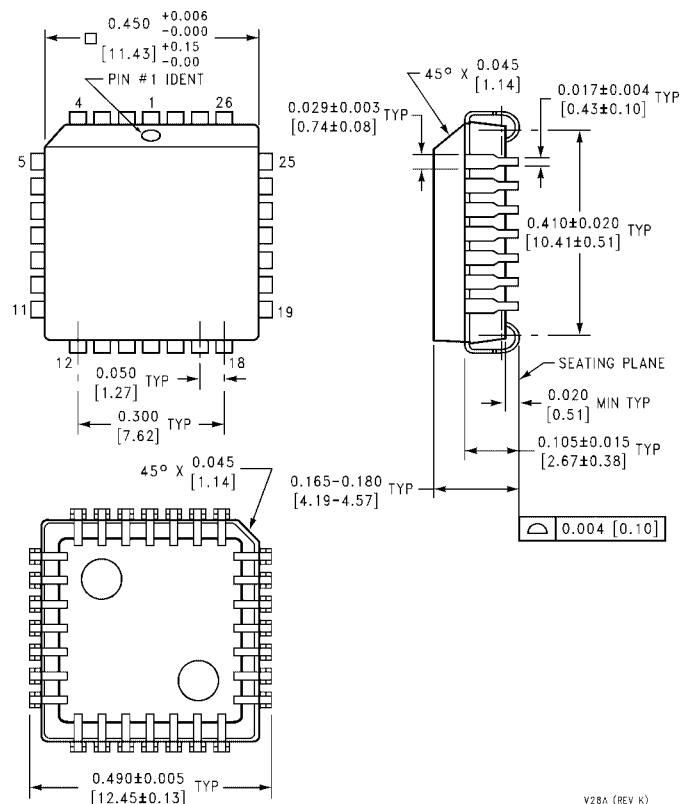
# Physical Dimensions inches (millimeters) unless otherwise noted



N24E (REV A)

**24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-010, 0.400 Wide  
Package Number N24E**

# Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**28-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.450 Square Package Number V28A**

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